SLVS050B - JUNE 1976 - REVISED JULY 1999

Temperature Compensated LP PACKAGE **Programmable Output Voltage** (TOP VIEW) Low Output Resistance Low Output Noise CATHODE Sink Capability up to 100 mA ANODE description REF The TL430 is a 3-terminal adjustable shunt regulator, featuring excellent temperature stability, wide operating current range, and low output noise. The output voltage can be set by two external resistors to any desired value between 3 V and 30 V. The TL430 can replace zener diodes in many applications, providing improved performance. REF. 3 B B CI The TL430C is characterized for operation from 0°C to 70°C. symbol ANODE AVAILABLE OPTIONS PACKAGED DEVICES **CHIP FORM** PLASTIC (Y) (LP) TL430CLP TL430Y $0^\circ C$ to $70^\circ C$ The LP package is available taped and reeled. Add R suffix to device

The LP package is available taped and reeled. Add R suffix to device type (e.g., TL430CLPR). Chip forms are tested at 25°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



Copyright © 1999, Texas Instruments Incorporated

SLVS050B - JUNE 1976 - REVISED JULY 1999

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Regulator voltage (see Note 1)	30 V
Continuous regulator current	150 mA
Package thermal impedance, θ_{JA} (see Notes 2 and 3):	156°C/W
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values are with respect to the anode terminal.

- 2. Maximum power dissipation is a function of $T_J(max)$, θ_{JA} , and T_A . The maximum allowable power dissipation at any allowable ambient temperature is $P_D = (T_J(max) T_A)/\theta_{JA}$. Operating at the absolute maximum T_J of 150°C can impact reliability.
- 3. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions

	MIN	MAX	UNIT	
Regulator voltage, VZ	B	Vref	30	V
Regulator current, IZ	A LA TA	2	100	mA
Operating free-air temperature range, TA	TL430C	0	70	°C
	1. 19			

electrical characteristics over recommended operating conditions, $T_A = 25^{\circ}C$ (unless otherwise noted)

PARAMETER		TEST	TEST CONDITIONS		TL430C			LINUT	
		FIGURE			MIN	TYP	MAX	UNIT	
V _{I(ref)}	Reference input voltage		$\forall Z = V_{I(ref)},$	I <u>Z</u> = 10 mA	2.5	2.75	3	V	
$\alpha V_{I(ref)}$	Temperature coefficient of reference input voltage	1	$V_Z = V_{I(ref)},$ $T_A = 0^{\circ}C \text{ to } 70^{\circ}C$	I <u>Z</u> = 10 mA,		120		ppm/°C	
II(ref)	Reference input current	2	I _Z = 10 mA, R2 = ∞	R1 = 10 kΩ,		3	10	μΑ	
IZK	Regulator current near lower knee of regulation range	1	$V_Z = V_{I(ref)}$			0.5	2	mA	
	Regulator current at maximum	1	$V_Z = V_{I(ref)}$		50			mA	
lzκ	K limit of regulation range		$V_Z = 5 V$ to 30 V,	See Note 4	100				
r _z	Differential regulator resistance (see Note 5)	1	$V_Z = V_{I(ref)},$ $\Delta I_Z = (52 - 2) mA$			1.5	3	W	
				V _Z = 3 V		50			
Vn	Noise voltage	2	f = 0.1 Hz to 10 Hz	V _Z = 12 V		200		μV	
				Vz = 30 V		650			

NOTES: 4. The average power dissipation, Vz • Iz • duty cycle, must not exceed the maximum continuous rating in any 10-ms interval.

5. The regulator resistance for $V_Z > V_{I(ref)}$, r_z , is given by:

$$\mathbf{r_{Z}}' = \mathbf{r_{Z}} \left(1 + \frac{\mathbf{R1}}{\mathbf{R2}} \right)$$



SLVS050B - JUNE 1976 - REVISED JULY 1999

electrical characteristics over recommended operating conditions, $T_A = 25^{\circ}C$ (unless otherwise noted)

PARAMETER		TEST	. TEST CONDITIONS		TL430Y			UNIT	
	PARAMETER	FIGURE		THONS	MIN	TYP	MAX	UNIT	
V _{I(ref)}	Reference input voltage	1	$V_Z = V_{I(ref)},$	I _Z = 10 mA	2.5	2.75	3	V	
II(ref)	Reference input current	2	I _Z = 10 mA, R2 = ∞	R1 = 10 kΩ,		3	10	μΑ	
IZK	Regulator current near lower knee of regulation range	1	$V_Z = V_{I(ref)}$			0.5	2	mA	
	Regulator current at maximum limit of regulation range	1	$V_Z = V_{I(ref)}$		50			mA	
		2	$V_{Z} = 5 V \text{ to } 30 V,$	See Note 4	100			IIIA	
r _Z	Differential regulator resistance (see Note 5)	1	$V_Z = V_{I(ref)}, \dots$ $\Delta I_Z = (52 - 2) \text{ mA}$			1.5	3	W	
			V _Z = 3 V		50				
Vn	Noise voltage	2	f = 0.1 Hz to 10 Hz	V _Z = 12 V		200		μV	
				V _Z = 30 V		650			

NOTES: 4. The average power dissipation, V_Z • I_Z • duty cycle, must not exceed the maximum continuous rating in any 10-ms interval.
5. The regulator resistance for V_Z > V_I(ref), r_z, is given by: REMENT

$$r_{z'} = r_{z} \left(1 + \frac{R1}{R2}\right)$$

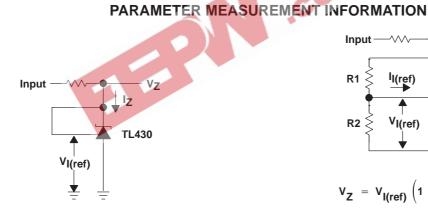


Figure 1. Test Circuit for V_Z = V_{I(ref)}

Input
$$V_Z$$

R1 $I_{I}(ref)$
R2 $V_{I}(ref)$
 $V_Z = V_{I}(ref) \left(1 + \frac{R1}{R2}\right) + I_{I}(ref) \times R1$

Figure 2. Test Circuit for V_Z > V_{I(ref)}



SLVS050B – JUNE 1976 – REVISED JULY 1999

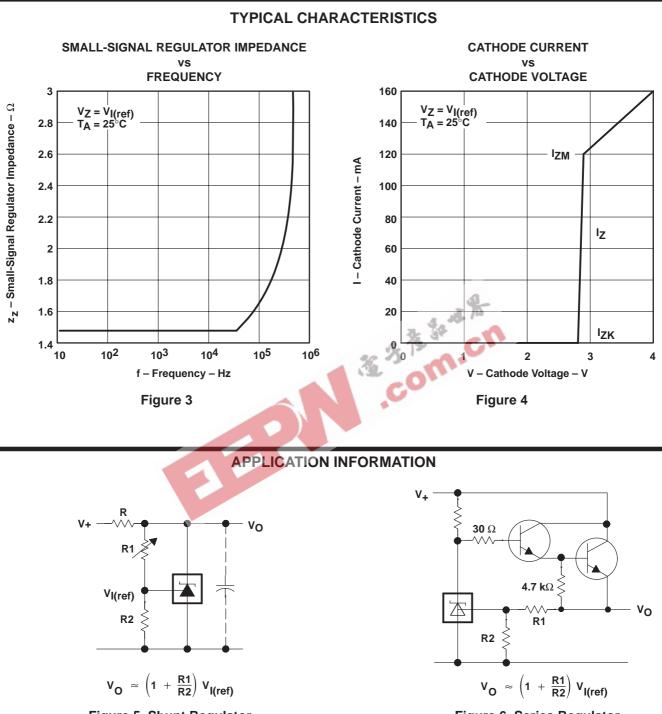




Figure 6. Series Regulator



SLVS050B - JUNE 1976 - REVISED JULY 1999

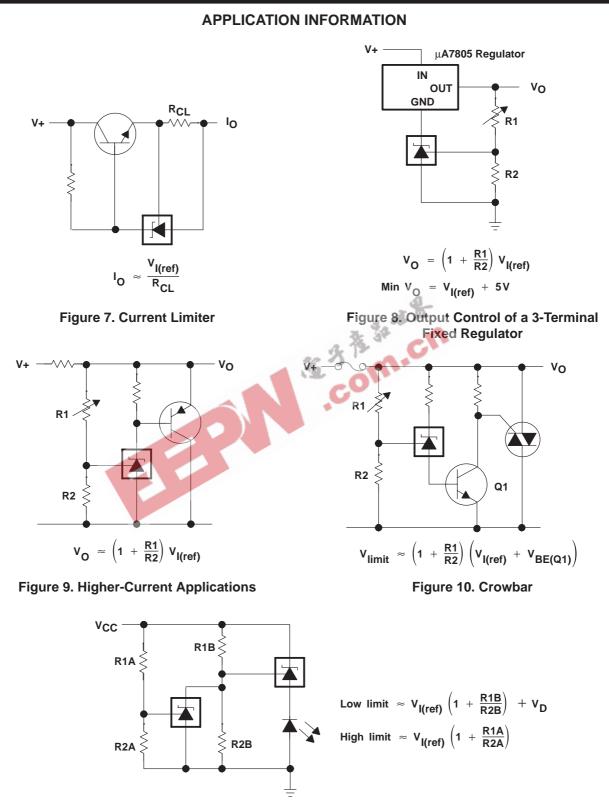


Figure 11. V_{CC} Monitor

POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.



Copyright © 1999, Texas Instruments Incorporated